- 1 -

## FIELD EFFECT TRANSISTOR, AND. SEMICONDUCTOR DEVICE MANUFACTURING METHOD

BACKGROUND OF THE INVENTION

## Field of the Invention

The present invention relates to a MOS (Metal Oxide Semiconductor) field effect transistor whose

5 blocking voltage appearing between a drain electrode and a substrate (between a drain electrode and a source electrode) is higher than 5 volts inclusive.

## Description of Related Art

For implementing a flash memory or the like

10 device which requires a voltage of about 10 volts or
higher for memory cell write/erase operations, there
are required MOS field effect transistors (MOSFETs)
whose blocking voltage is on the order of 10 volts.

In Japanese Patent Application Laid-Open Publication

15 No. 86580/1995 (JP-A-7-86580), a MOS field effect
transistor which exhibits a relatively high blocking
voltage of about 30 volts and in which a high-density
layer formed in contact with a drain electrode is
disposed relative to a high-density layer formed in

20 contact with the source electrode with interposition of
an insulation film having a thickness greater than a
gate insulation film.

Further, as the MOS field effect transistor